


# Schedule of Accreditation

issued by

## United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 <b>29722</b>  Accredited to ISO/IEC 17025:2017	<b>Retronix Ltd</b>	
	<b>Issue No:</b> 003	<b>Issue date:</b> 16 September 2025
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<b>Testing performed at the above address only</b>		

### DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ENGINEERING MATERIAL, MACHINERY, STRUCTURES AND PRODUCTS  Electronics/Semiconductors  Electrical, Electronic, and Electromechanical (EEE) parts to mitigate the risks of receiving or using Suspect/Counterfeit (SC) EEE parts	<u>Elemental Analysis</u>	
	Suspect/Counterfeit Test Evaluation Methods	Aerospace Standard SAE AS6171:2018 tests methods.  For counterfeit defect and counterfeit type coverages by a sequence of tests, using a Model assignment, Moderate risk model 2
	AS6171/2 Detection by External Visual Inspection (EVI), Remarking and Resurfacing, and Surface Texture	Visual and high magnification inspection to detect recycled or counterfeit products (i.e., removed from boards or assemblies and reworked by straightening of leads, retinning the leads, removal of the original marking and remarking, and/or blacktopping the component to hide evidence of the remarking and counterfeiting). Excluding AS 6171/2 METHOD F (SEM)
	AS6171/3: Detection by X-ray Fluorescence (XRF) test methods	Analysis of elements Pb, Cu, Zn, Ni, Ag Sn The plating layer thicknesses, presence of barrier materials, and the base material from some expected material compositions.



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ENGINEERING MATERIAL, MACHINERY, STRUCTURES AND PRODUCTS (cont'd)  Electronics/Semiconductors (cont'd)  Electrical, Electronic, and Electromechanical (EEE) parts to mitigate the risks of receiving or using Suspect/Counterfeit (SC) EEE parts (cont'd)	<u>Elemental Analysis</u> (cont'd)  AS6171/4: Detection by Delid/Decapsulation Physical Analysis (DDPA) using in house test methods RTS-TL-SOP-005  AS6171/5: Detection by Radiological (X-ray) test methods  AS6171/7: Detection by Electrical Test Methods	To verify that die attributes are consistent with the known manufacturer of the device.  To examine the internal and external attributes of a part in order to detect deliberate misrepresentation or damage, which could indicate a suspect counterfeit part. Parts are inspected for homogeneity, consistency, and uniformity.  Electrical testing to verify performance to the published electrical specifications. Covering DC curve trace, Full DC tests at ambient temperatures and over the parts full operating temperature range. Environmental Tests, consisting of Temperature Cycling for active parts.
END		